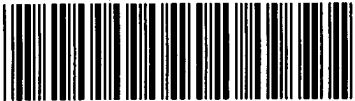


Search Notes 	Application/Control No. 09925397	Applicant(s)/Patent Under Reexamination CHANG ET AL.
	Examiner Ehichioya, Fred I	Art Unit 2162

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
IEEE Xplore	12/16/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	12/17/07	FE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner